

**Notice of References Cited**

Application/Control No.

10/574,319

Applicant(s)/Patent Under  
Reexamination  
SUN ET AL.

Examiner

GREG BENZON

Art Unit

2444

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,983,334 B2	01-2006	Riedle, Linda Ann	709/250
*	B	US-6,185,623 B1	02-2001	Bailey et al.	709/238
*	C	US-2008/0168157 A1	07-2008	Marchand, Benoit	709/219
*	D	US-7,305,585 B2	12-2007	Marchand, Benoit	714/18
*	E	US-2003/0088667 A1	05-2003	Riedle, Linda Ann	709/224
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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